

Notice of References Cited	Application/Control No. 10/786,811	Applicant(s)/Patent Under Reexamination ZHENG ET AL.	
	Examiner Dawn Garrett	Art Unit 1774	Page 1 of 1

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*	B	US-6,803,124	10-2004	Taguchi, Toshiki	428/690
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NON-PATENT DOCUMENTS

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	U	Peng et al., Chemtech, 29(5), p. 41-46, 1999.
	V	Lee et al., Chem. Materials, 2001, 13, p. 565-574.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.